

ST-UNICT cooperation for «testing otiented» projets

LGS PE team

Design For Test for Analog

- Feasibility and advantages for LGS products
- Impact on Failure Rate and analog coverage evaluation
- Example:
 - https://www.researchgate.net/publication/220751644_Power-scan_chain_Design_for_analog_testability

Contact Prof. A.D. Grasso



Design For Test for DC-DC converter

- Closed loop parameters analysis vs target spec
- DFT for closed loop parameters evaluation through open loop or DC parameters measurements
- Relationship between closed loop and open loop parameters:
 - Choice of parameters and limits

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Hardware Development to improve Test Solution

- Development of new hardware solutions to bypass ATE limitation and improve testing efficiency:
 - Development of new floating voltage generator
 - Optimization of Current Pulse generator for Current limitation test
 - Characterizations of photoemitting circuits

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